

Notice of References Cited	Application/Control No. 10/796,514	Applicant(s)/Patent Under Reexamination SNYDER ET AL.	
	Examiner Su C. Kim	Art Unit 2823	Page 1 of 1

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	C	US-4,312,113	01-1982	Calviello, Joseph A.	438/572
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NON-PATENT DOCUMENTS

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	U	Byiung Hun Lee et al. ,Dec. 1999, IEDM Technical Digest, international 5-8, pages 133-136
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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